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**Aehr Test Systems to Participate in the Fifth Annual Midtown CAP
Investor Summit in New York**

Fremont, CA (December 2, 2016) - Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that Gayn Erickson, President and CEO, will participate in the Fifth Annual Midtown CAP Investor Summit 2016 being held December 8, 2016 at Le Parker Meridien Hotel in New York City.

Aehr Test will post its presentation materials used at the conference on the Investor Relations section of the Company's website at www.aehr.com.

"We look forward to discussing how our new FOX wafer level test and burn-in products provide unique and highly valuable test and burn-in solutions for our customers and are positioning Aehr Test for future growth and success in the growing integrated circuit and sensor reliability and test markets," said Erickson. "These markets include stacked flash memory for enterprise Solid State Drive applications, automotive infotainment and advanced driving assistance systems, and mobility applications for smartphones and wearable devices. Our new products include unique single and multi-wafer burn-in and test systems that offer low-cost, highly parallel testing solutions to improve reliability and yield of our customers' products."

The Midtown CAP Summit is hosted by executive management from the following participating companies: Aehr Test Systems (AEHR), Axcelis (ACLS), Advanced Energy Industries (AEIS), Brooks Automation (BRKS), Camtek Ltd (CAMT), Cohu (COHU), Electro Scientific Industries (ESIO), FormFactor (FORM), inTEST Corporation (INTT), Intevac (IVAC), Kulicke & Soffa (KLIC), Nanometrics (NANO), Rudolph Technologies (RTEC), Ultratech (UTEK), and Xcerra Corporation (XCRA), and will feature a "round-robin" format consisting of a series of small group meetings.

The Midtown CAP Summit is by invitation only and is open to accredited investors and publishing research analysts.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and WaferPak contactors. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital

signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on AeHR Test FOX systems. For more information, please visit AeHR Test's website at www.aehr.com.

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